TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (π -MOSVI)

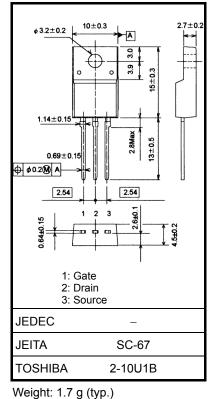
2SK3766

Switching Regulator Applications

- Low drain-source ON resistance: $RDS(ON) = 1.9 \Omega(typ.)$
- High forward transfer admittance: $|Y_{fs}| = 0.65 \text{ S}$ (typ.)
- Low leakage current: $I_{DSS} = 100 \ \mu A \ (max) \ (V_{DS} = 450 \ V)$
- Enhancement model: $V_{th} = 3.5 \sim 4.5 \text{ V} (V_{DS} = 10 \text{ V}, \text{ID} = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

| Characteristic | | Symbol | Rating | Unit | |
|-----------------------|--------------------------|------------------|---------|------|--|
| Drain-source voltage | <u>)</u> | V _{DSS} | 450 | V | |
| Drain-gate voltage (F | R _{GS} = 20 kΩ) | V _{DGR} | 450 | V | |
| Gate-source voltage | | V _{GSS} | ±30 | V | |
| Drain current | DC (Note 1) | ۱ _D | 2 | Α | |
| | Pulse (Note 1) | I _{DP} | 5 | ~ | |
| Drain power dissipat | ion (Tc = 25°C) | PD | 30 | W | |
| Single pulse avalance | the energy (Note 2) | E _{AR} | 103 | mJ | |
| Avalanche current | | I _{AR} | 2 | А | |
| Repetitive avalanche | e energy (Note 3) | E _{AR} | 3 | mJ | |
| Channel temperature | Э | T _{ch} | 150 | °C | |
| Storage temperature | range | T _{stg} | -55~150 | °C | |



Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

Thermal Characteristics

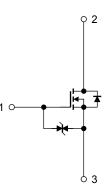
| Characteristic | Symbol | Max | Unit | |
|--|------------------------|------|------|--|
| Thermal resistance, channel to case | R _{th (ch-c)} | 4.17 | °C/W | |
| Thermal resistance, channel to ambient | R _{th (ch-a)} | 62.5 | °C/W | |

Note 1: Ensure that the channel temperature does not exceed 150°C during use of the device.

Note 2: $V_{DD} = 90 \text{ V}, \text{ T}_{ch} = 25^{\circ}\text{C}$ (initial), L = 42.8 mH, R_G = 25 Ω , I_{AR} = 2 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.



Unit: mm

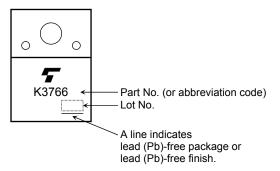
Electrical Characteristics (Ta = 25°C)

| Chara | acteristic | Symbol | Test Condition | Min | Тур. | Max | Unit |
|------------------------------|--------------------|----------------------|--|------|------|------|------|
| Gate leakage current | | I _{GSS} | $V_{GS}=\pm 25~V,~V_{DS}=0~V$ | _ | _ | ±10 | μA |
| Gate-source breal | kdown voltage | V (BR) GSS | $I_G=\pm 10~\mu A,~V_{DS}=0~V$ | ±30 | | | V |
| Drain cutoff current | | I _{DSS} | $V_{DS} = 450 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ | _ | | 100 | μA |
| Drain-source brea | kdown voltage | V (BR) DSS | $I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$ | 450 | | | V |
| Gate threshold voltage | | V _{th} | $V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$ | 3.5 | | 4.5 | V |
| Drain-source ON resistance | | R _{DS (ON)} | $V_{GS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ A}$ | _ | 1.9 | 2.45 | Ω |
| Forward transfer admittance | | Y _{fs} | $V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ A}$ | 0.18 | 0.65 | _ | S |
| Input capacitance | | C _{iss} | V_{DS} = 25 V, V_{GS} = 0 V, f = 1 MHz | _ | 270 | | pF |
| Reverse transfer capacitance | | C _{rss} | | _ | 4 | | |
| Output capacitanc | Output capacitance | | | _ | 45 | _ | |
| Switching time | Rise time | tr | $V_{GS}^{10 \text{ V}} \downarrow_{DD} = 1 \text{ A} \\ V_{GS}^{0 \text{ V}} \downarrow_{DD} = 1 \text{ A} \\ R_{L} = 200 \Omega \\ V_{DD} \approx 200 \text{ V} $ Duty $\leq 1\%, t_{W} = 10 \ \mu \text{s}$ | _ | 20 | | - ns |
| | Turn-on time | t _{on} | | _ | 30 | _ | |
| | Fall time | t _f | | _ | 18 | _ | |
| | Turn-off time | t _{off} | | _ | 60 | _ | |
| Total gate charge | | Qg | | | 8 | | |
| Gate-source charge | | Q _{gs} | $V_{DD}\simeq 360~V,~V_{GS}=10~V,~I_{D}=2~A$ | | 4 | | nC |
| Gate-drain charge | | Q _{gd} | | | 4 | | |

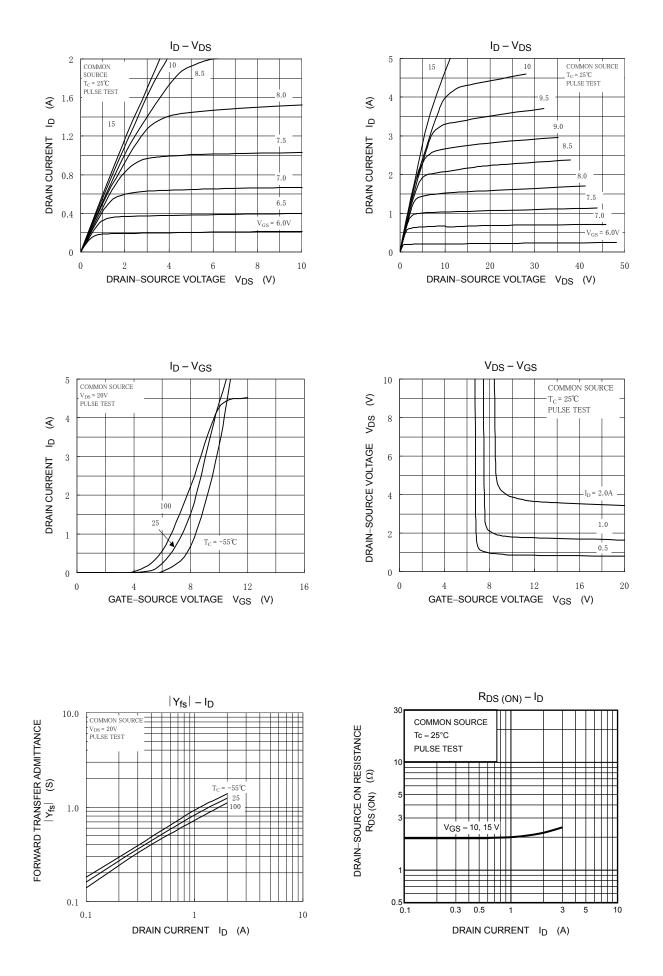
Source-Drain Ratings and Characteristics (Ta = 25°C)

| Characteristic | Symbol | Test Condition | Min | Тур. | Max | Unit |
|---|------------------|--|-----|------|------|------|
| Continuous drain reverse current (Note 1) | I _{DR} | — | _ | _ | 2 | А |
| Pulse drain reverse current (Note 1) | I _{DRP} | — | _ | _ | 5 | А |
| Forward voltage (diode) | V _{DSF} | $I_{DR} = 2 \text{ A}, \text{ V}_{GS} = 0 \text{ V}$ | _ | _ | -1.5 | V |
| Reverse recovery time | t _{rr} | $I_{DR} = 2 \text{ A}, V_{GS} = 0 \text{ V},$ | _ | 1000 | _ | ns |
| Reverse recovery charge | Q _{rr} | dl _{DR} /dt = 100 A/μs | | 5.0 | | μC |

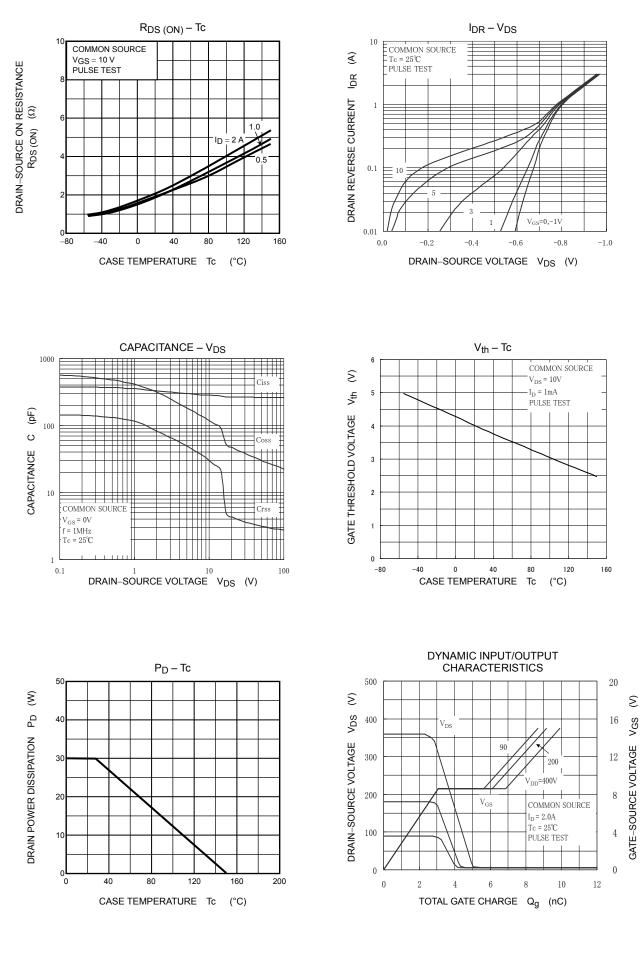
Marking

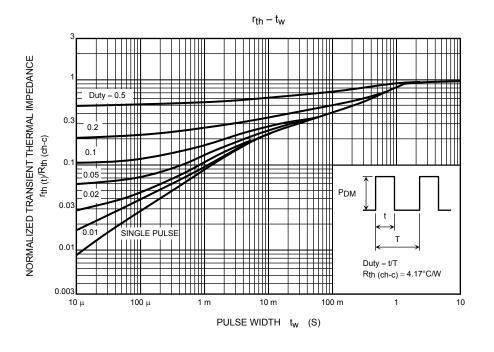


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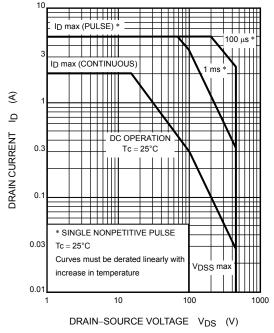


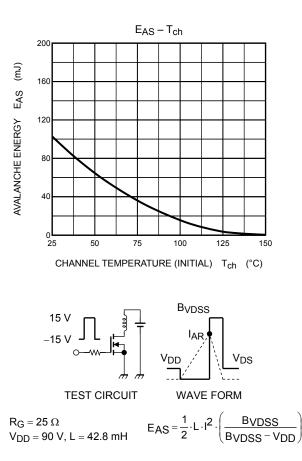
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SAFE OPERATING AREA





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